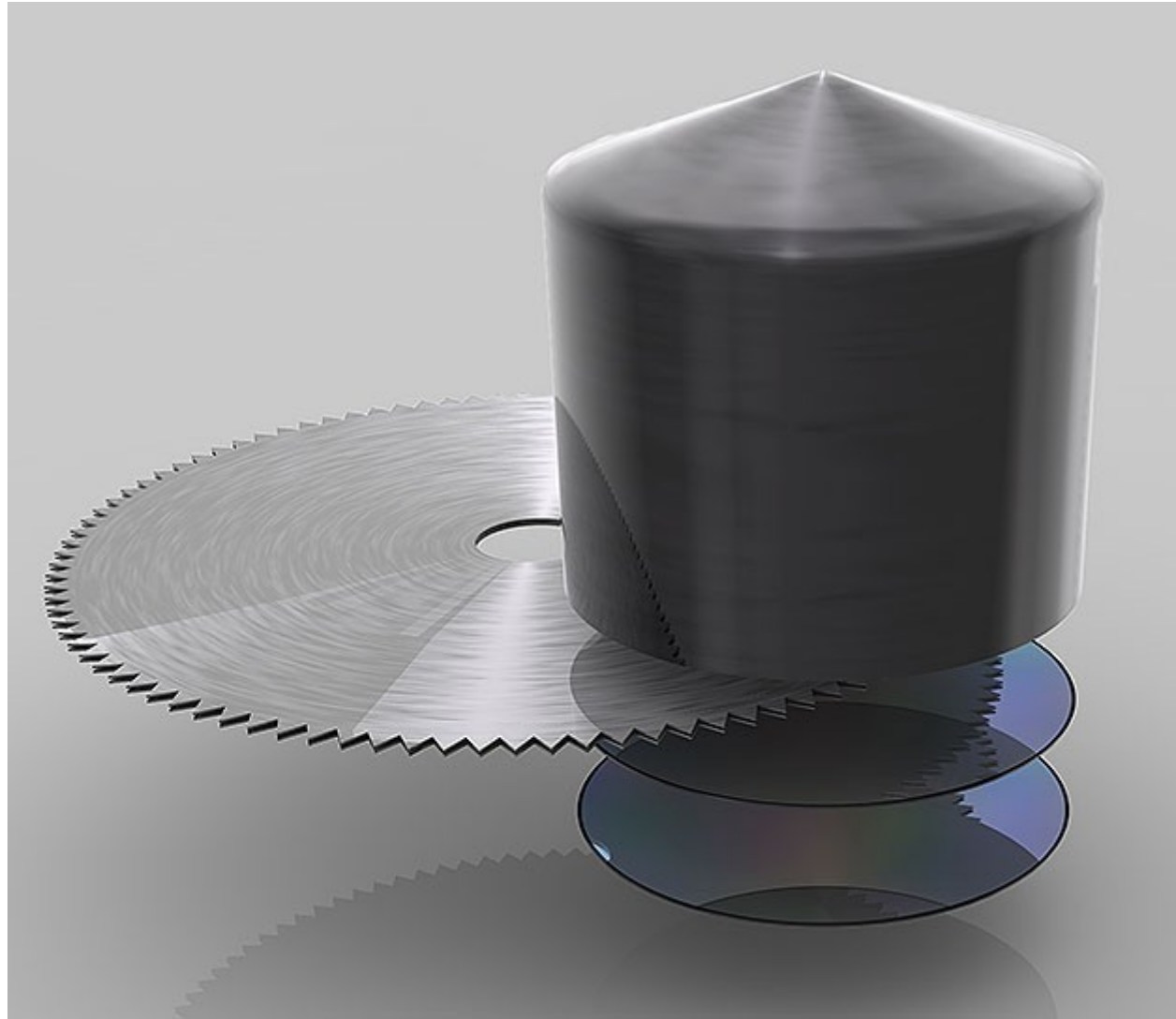
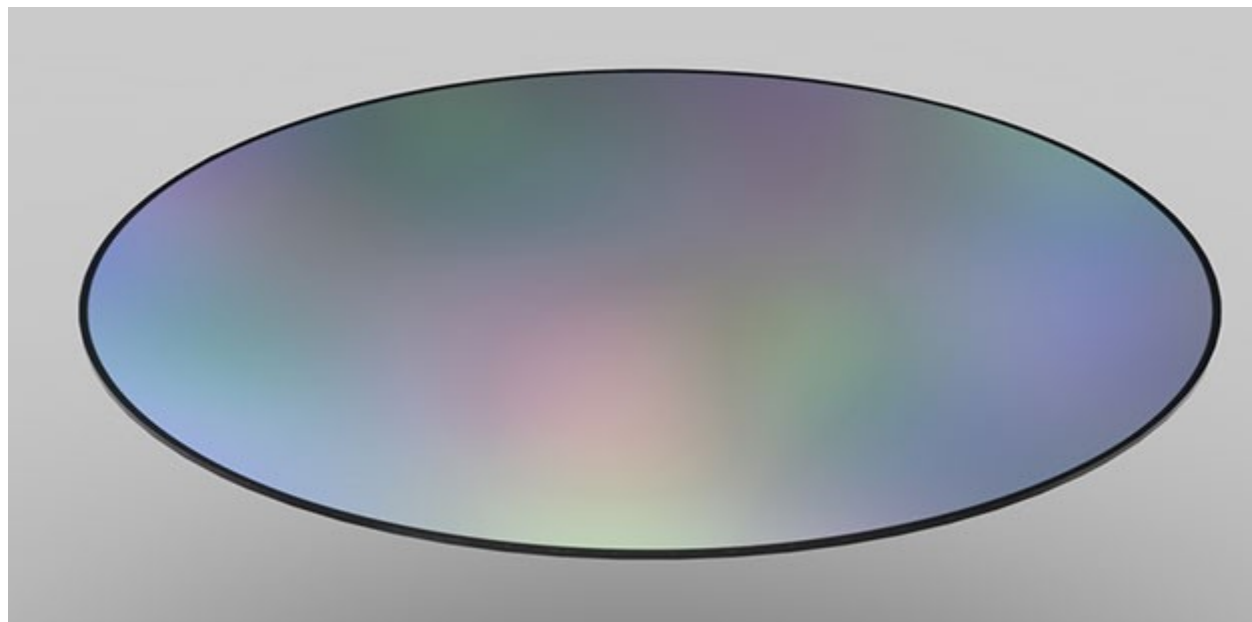


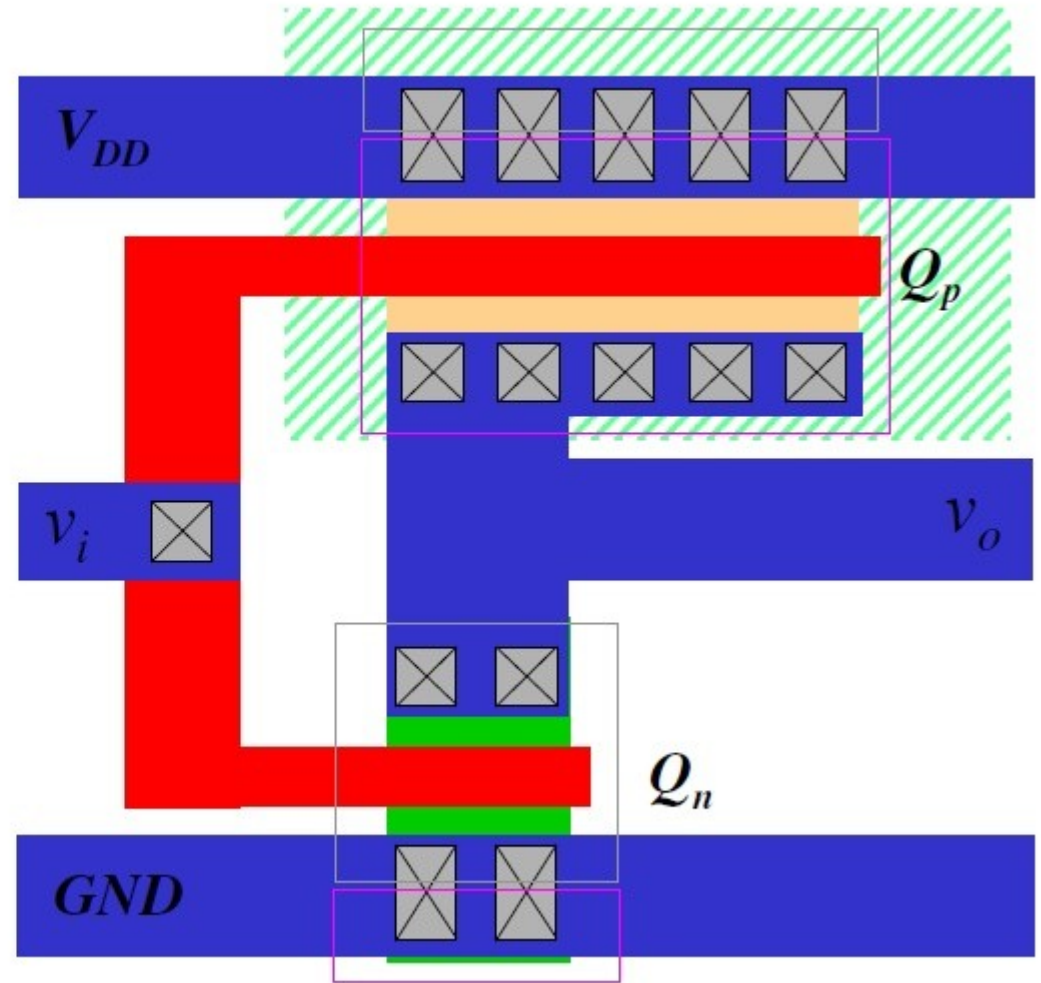
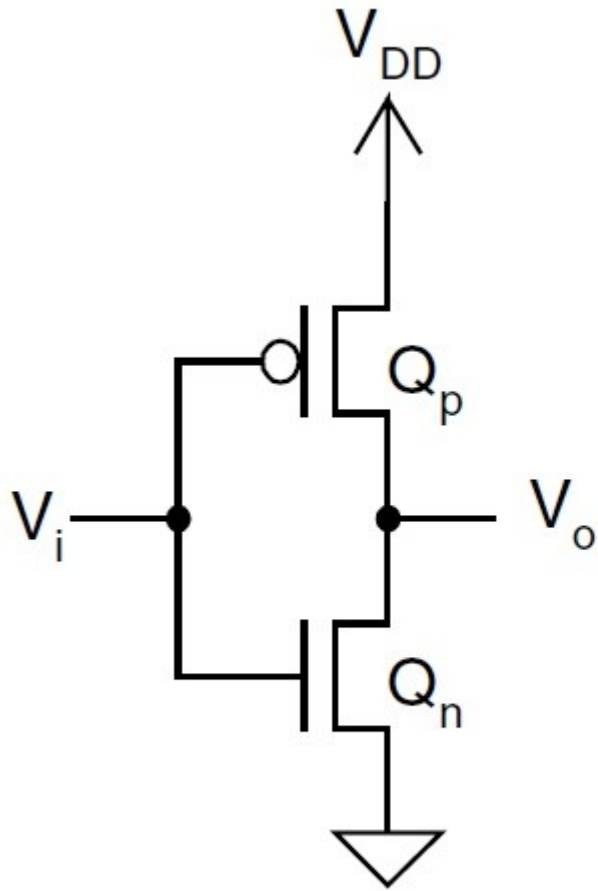
IC Fabrication

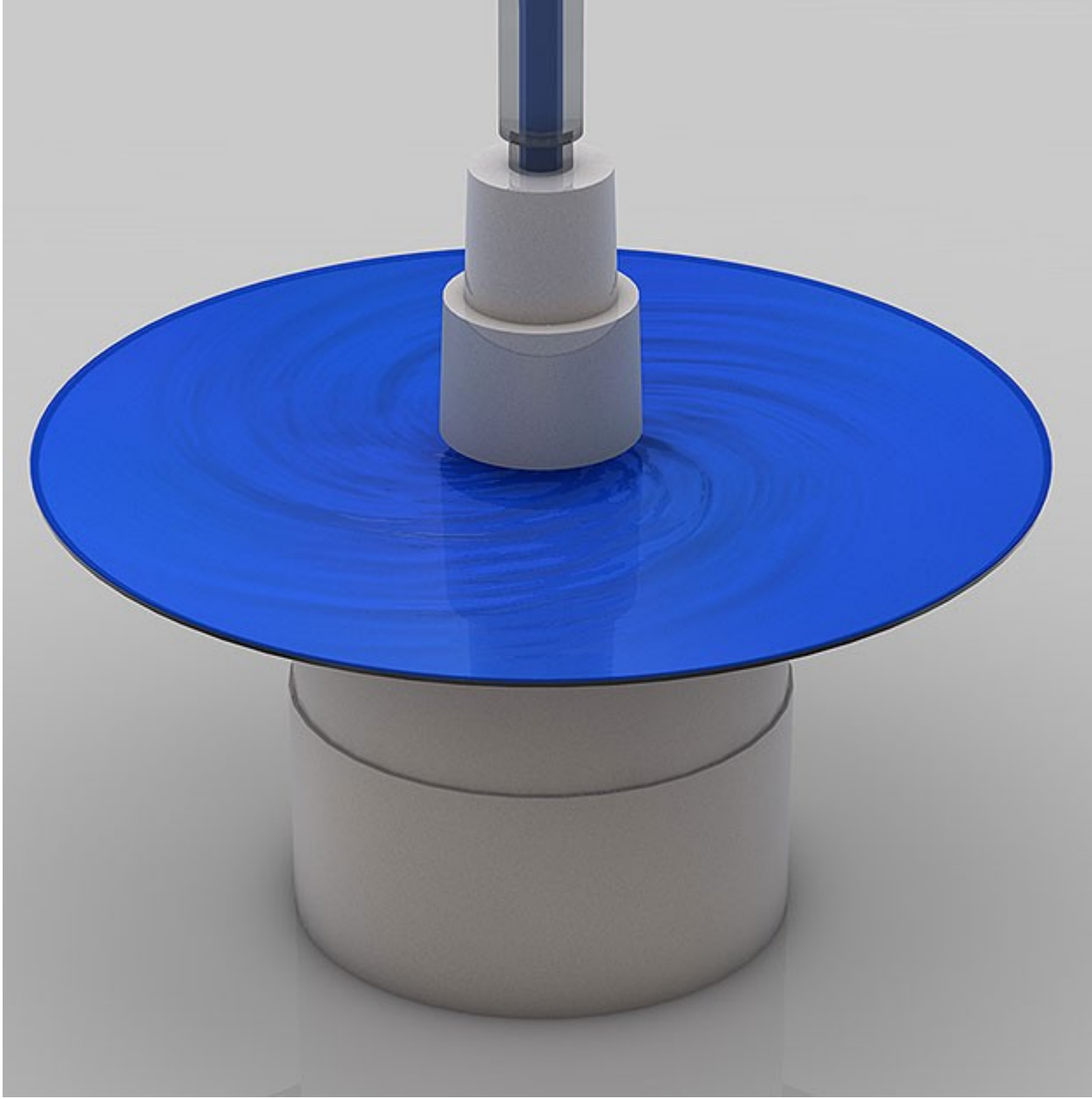


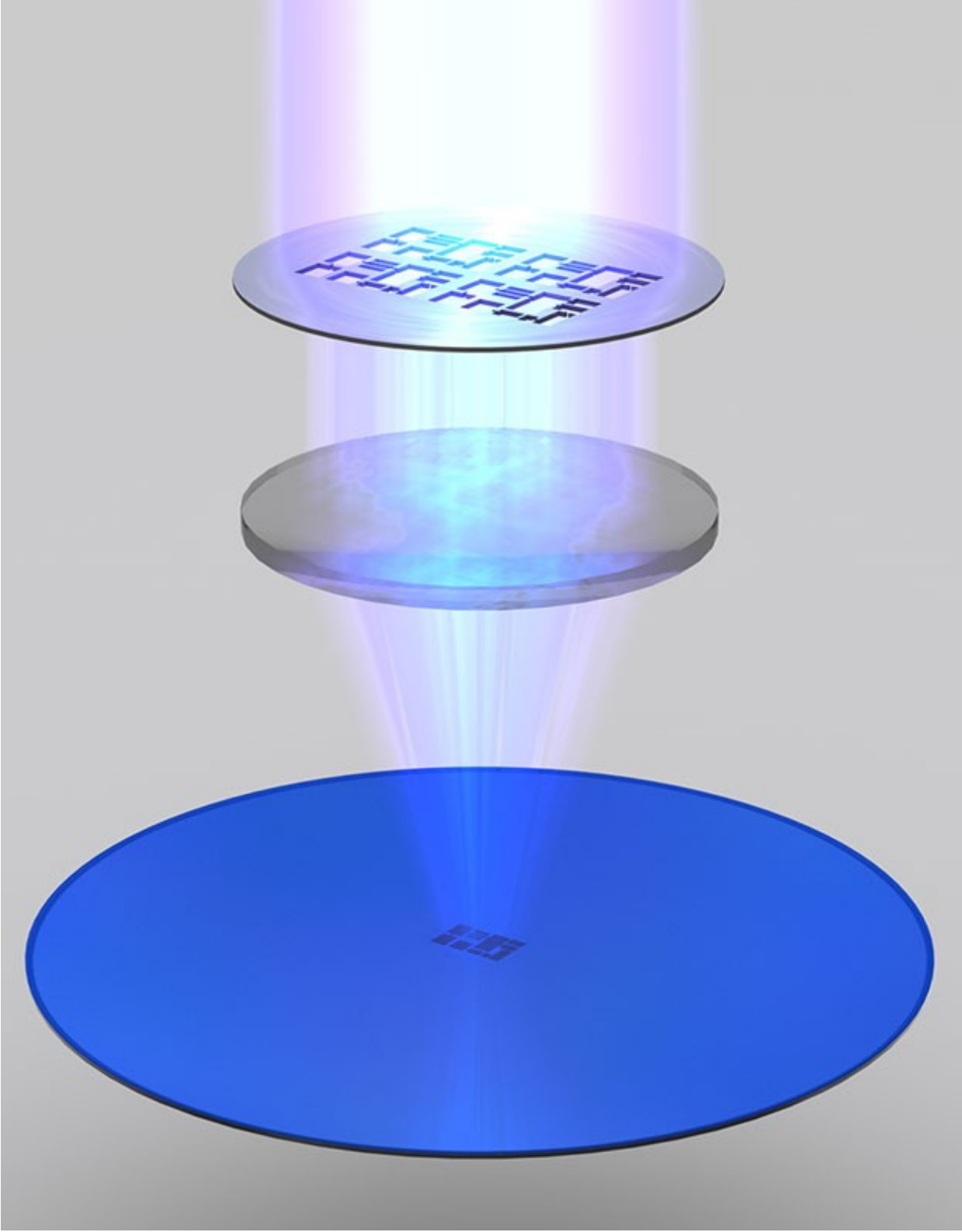




CMOS Inverter

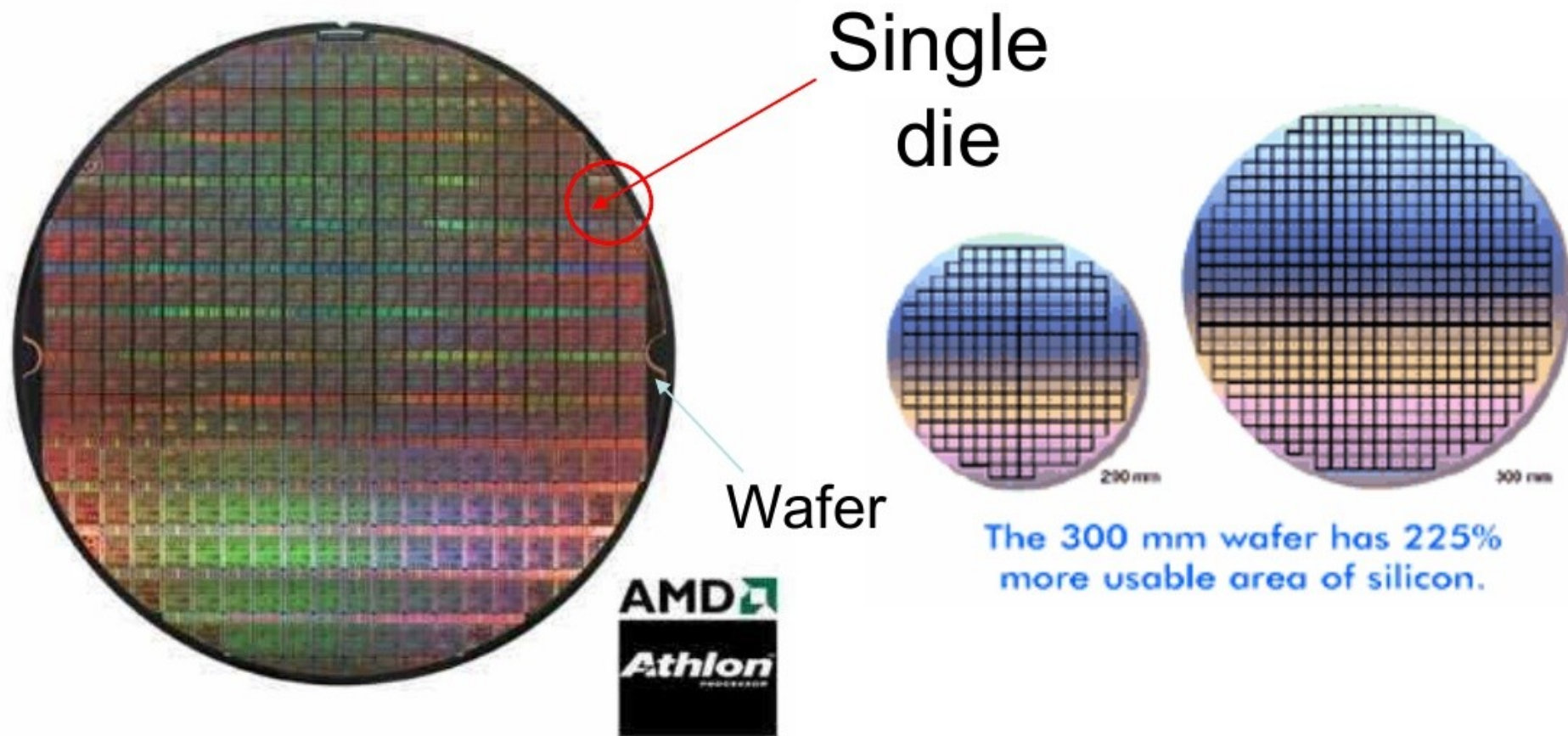






晶片的大小

- 晶圓的照片 (Wafer photo)

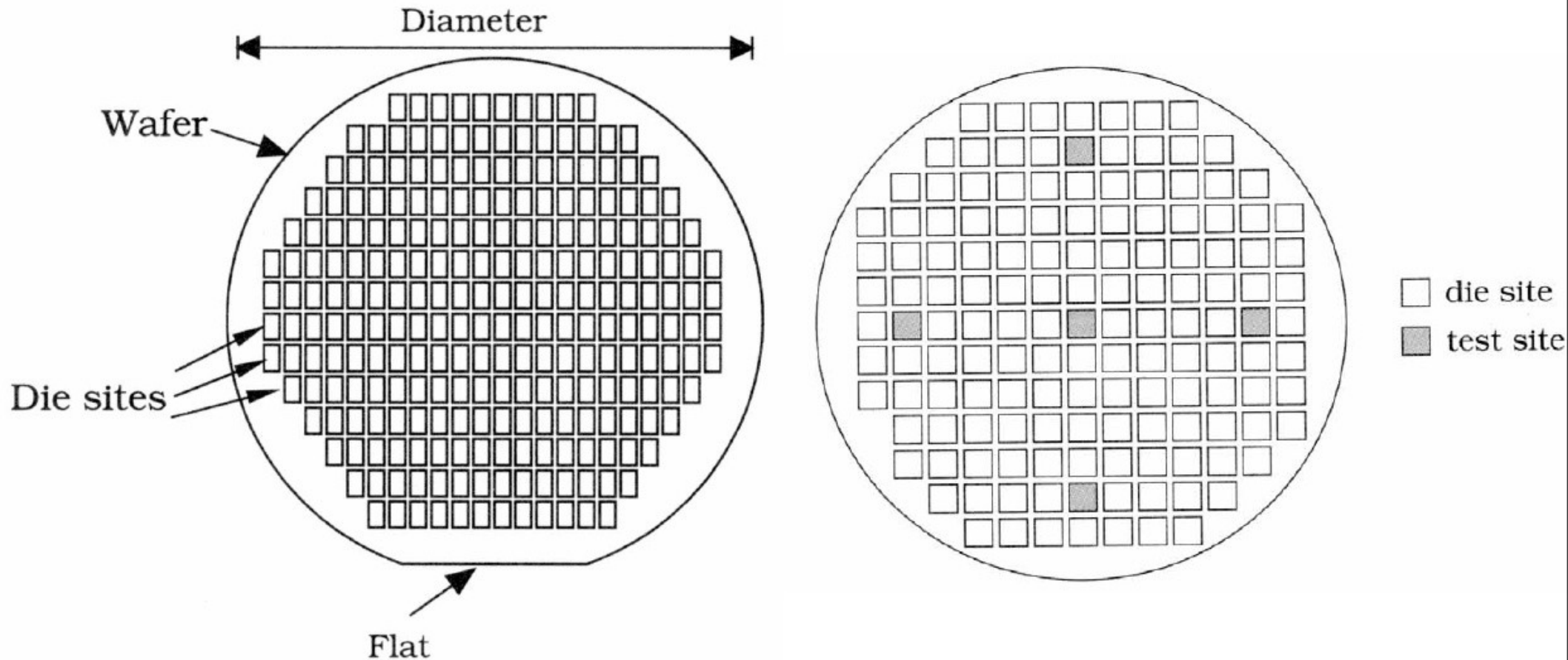


From <http://www.amd.com>

已提昇至 12" (30cm)

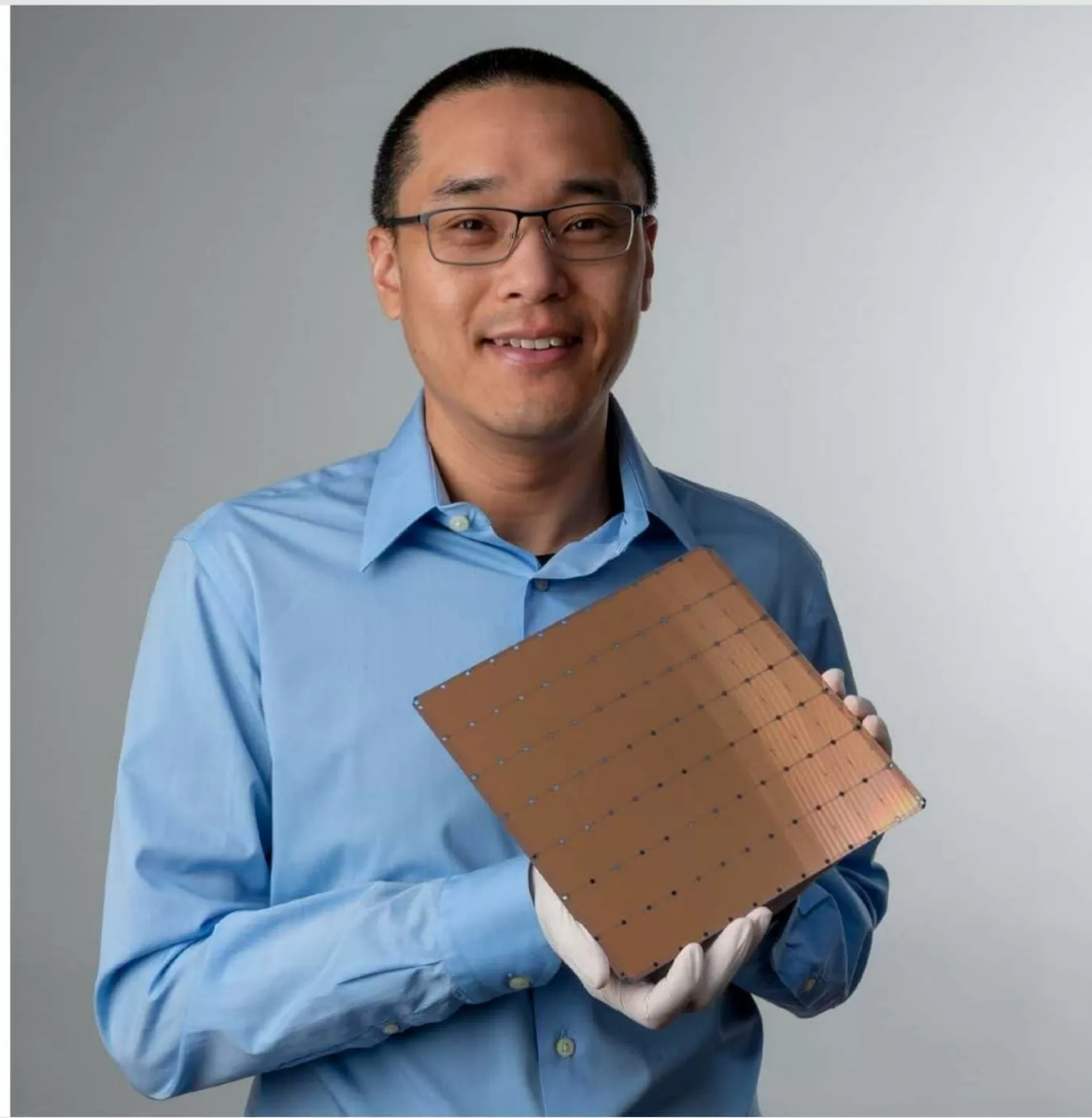
Wafer, Die, and IC

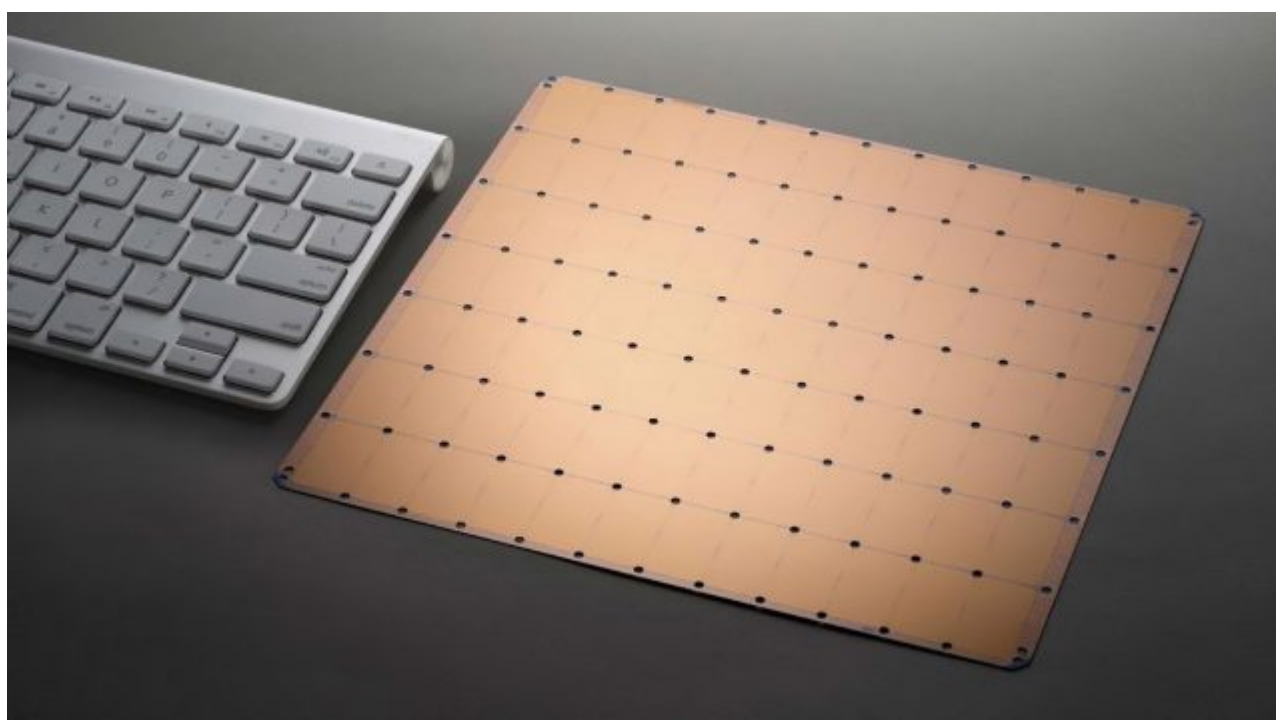
- Yield
- Defect density



Largest Chip Ever Built

- 46,225 mm² silicon
- 1.2 trillion transistors
- 400,000 AI optimized cores
- 18 Gigabytes of On-chip Memory
- 9 PByte/s memory bandwidth
- 100 Pbit/s fabric bandwidth
- TSMC 16nm process





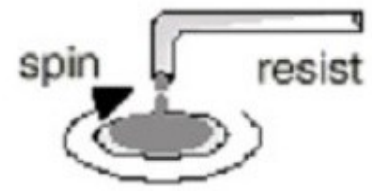
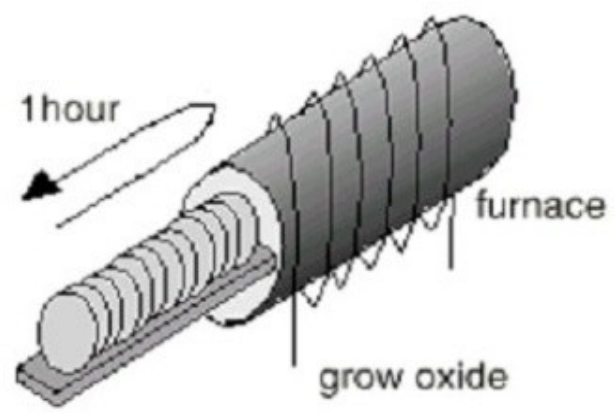
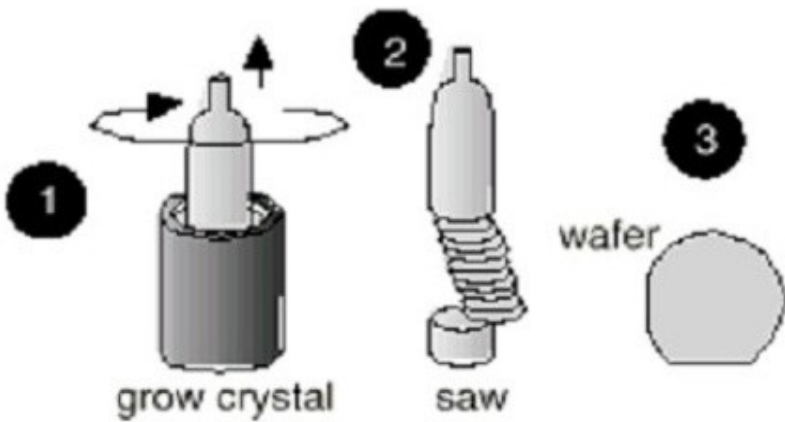
Wafer Scale Engine – Generation 2

850,000 AI-optimized cores

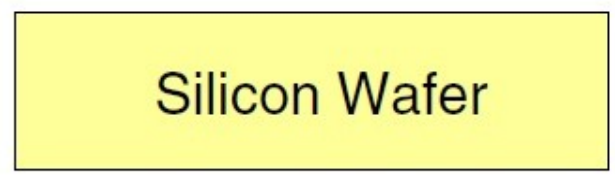
2.6 Trillion Transistors

TSMC 7nm Process

The CMOS process -> Photolithography



(a) Bare silicon wafer



(b) Grow Oxide layer

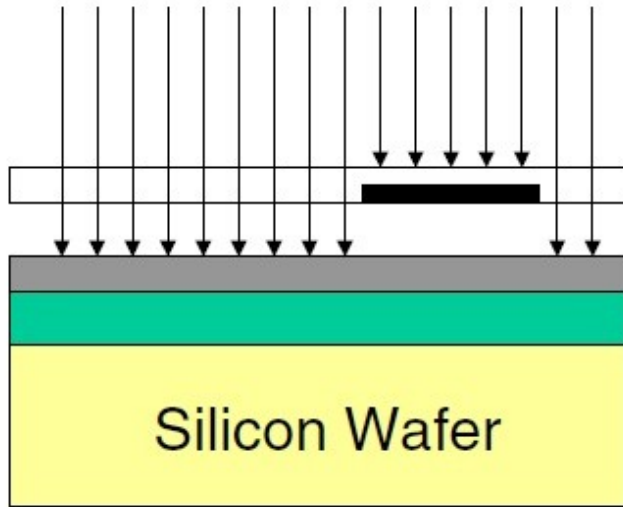


(c) Spin on photoresist



Photolithography - continued

(d) Expose resist to UV light through a MASK



(e) Remove unexposed resist



(f) Etch away oxide



(g) Remove remaining resist



Silicon Dioxide (SiO_2)

- Thin oxide, using dry oxidation
 - Material under the gate terminal of MOS
- Thick oxide (field oxide), using wet oxidation
 - Isolation between MOS
- CVD (chemical vapor deposition) oxide
 - Isolation between layers

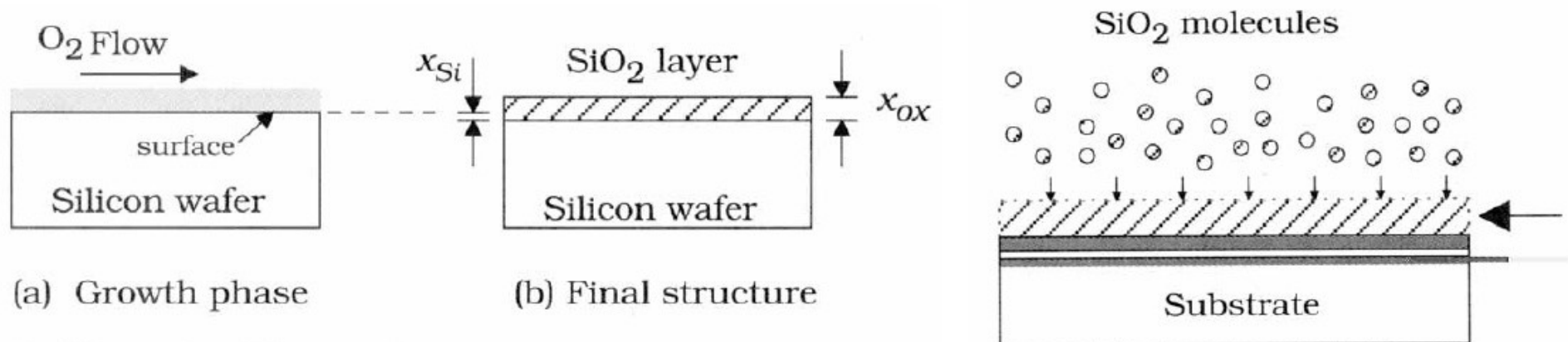
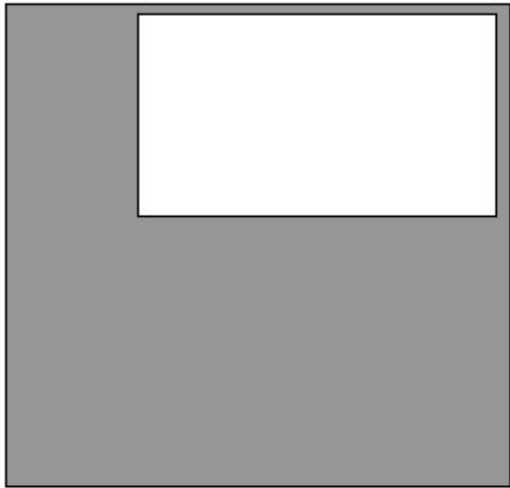


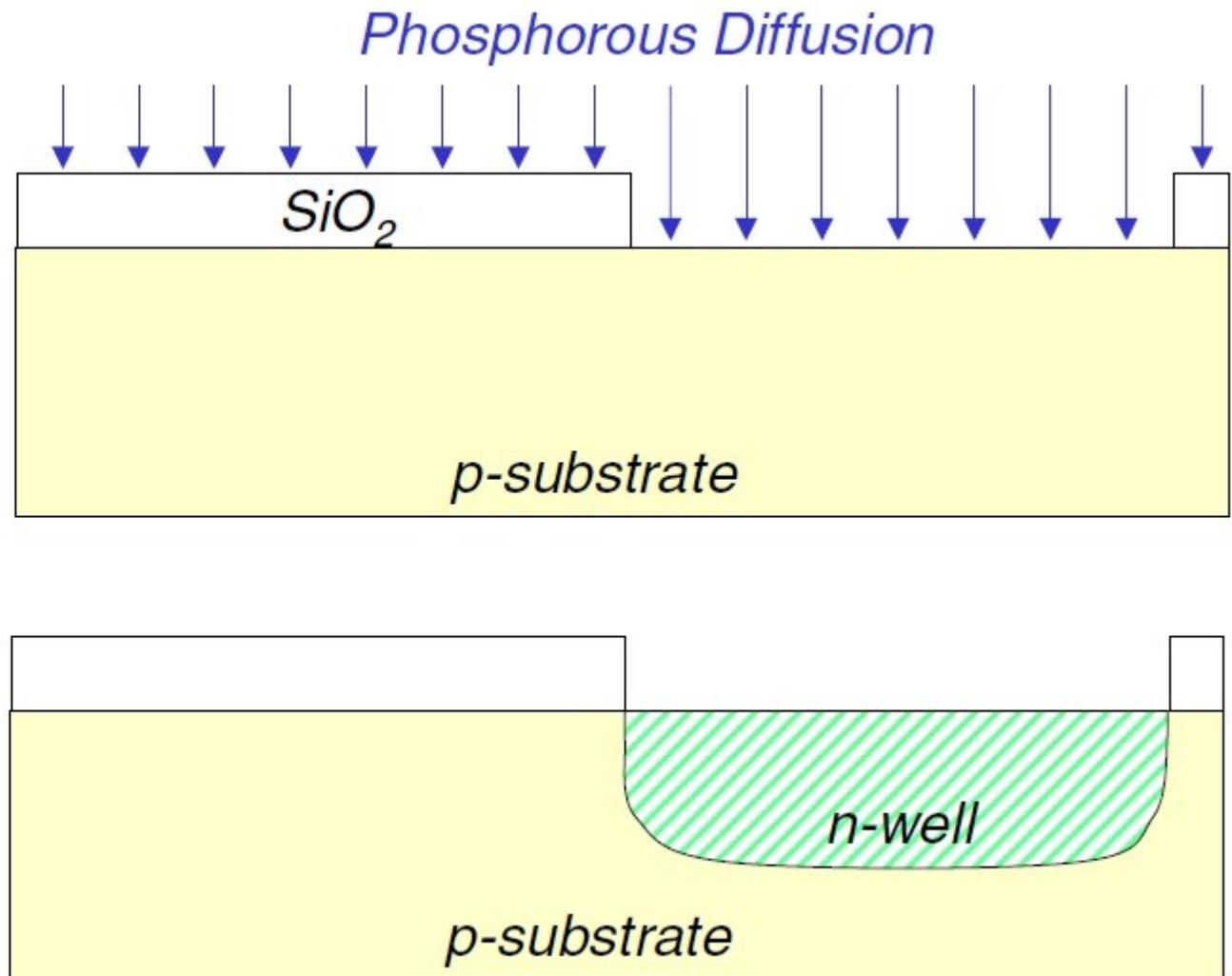
Figure 4.2 Thermal oxide growth

Mask 1 : N-well Diffusion

- SiO_2 is etched using *Mask 1*.

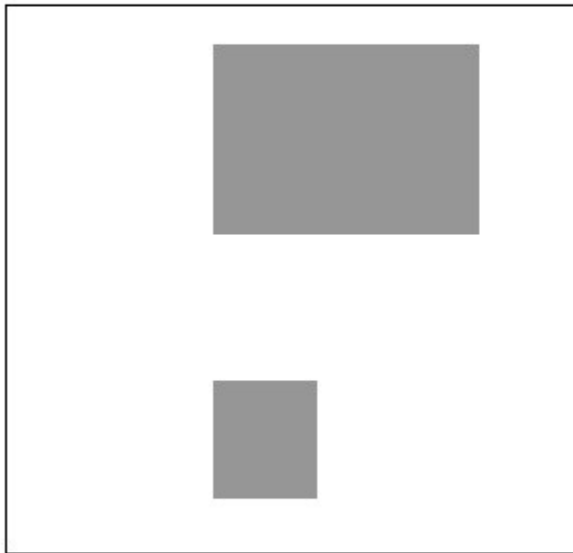


- *Phosphorous is diffused into the unmasked regions of silicon creating an n-well for the fabrication of p-channel devices*

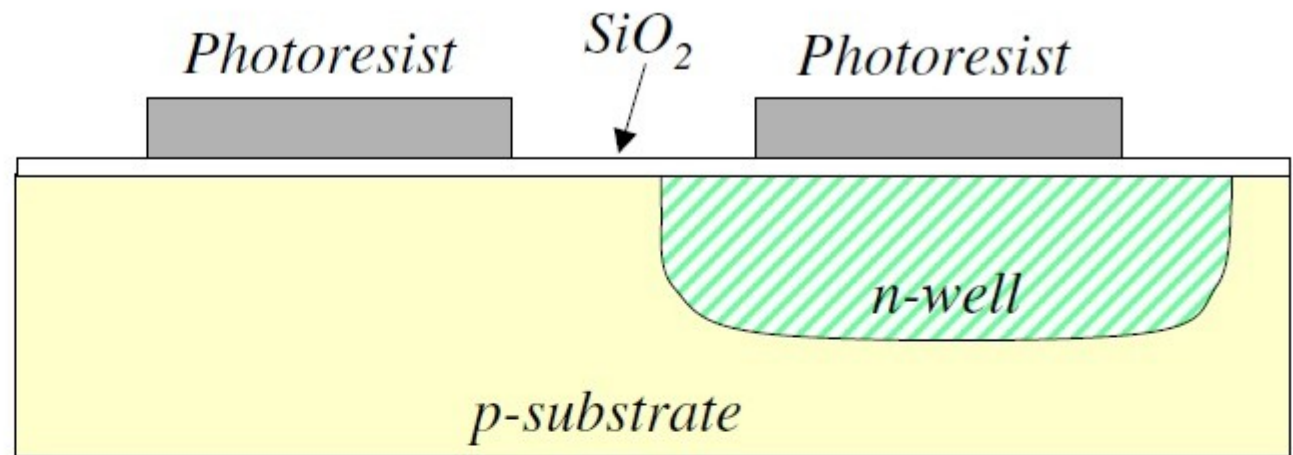


Mask 2 : Define Active Regions

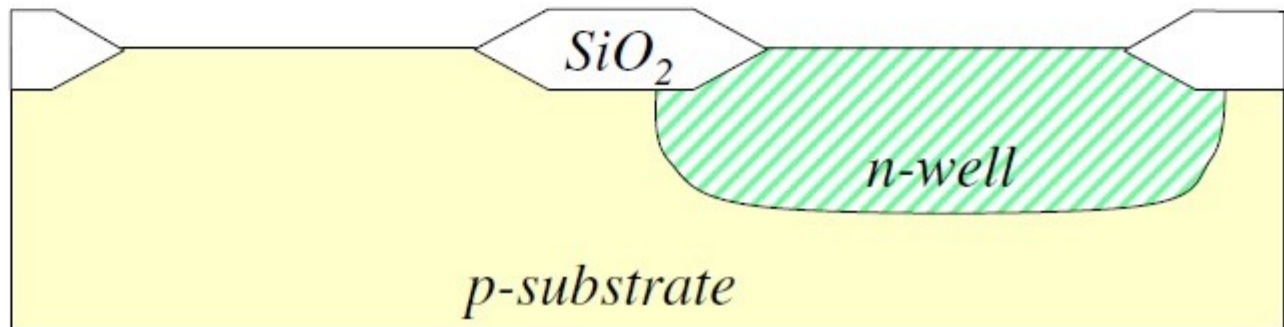
- *Mask 2 creates the active regions where the MOSFETs will be placed*



- *The thick oxide regions provides isolation between the MOSFETs*

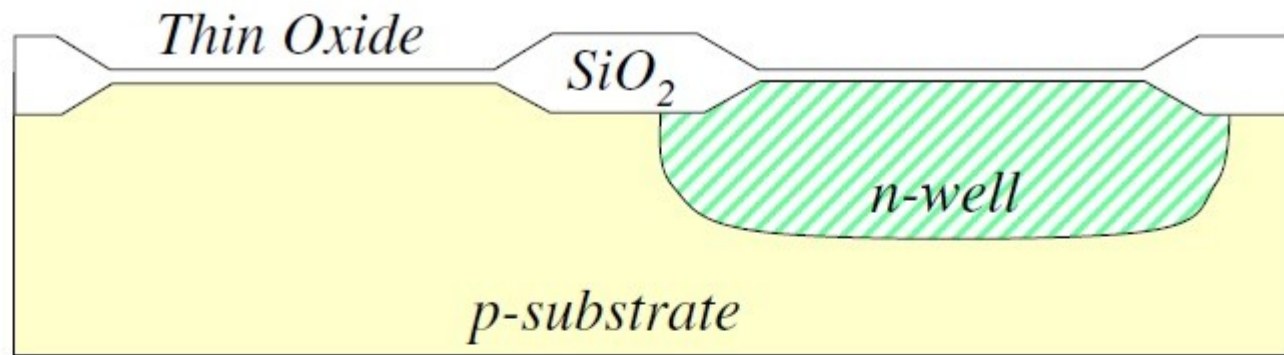
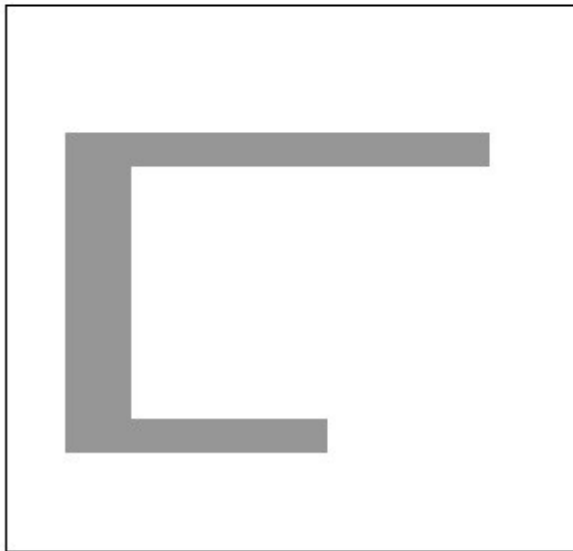


A thick field oxide is grown using a construction technique called Local Oxidation Of Silicon (LOCOS).

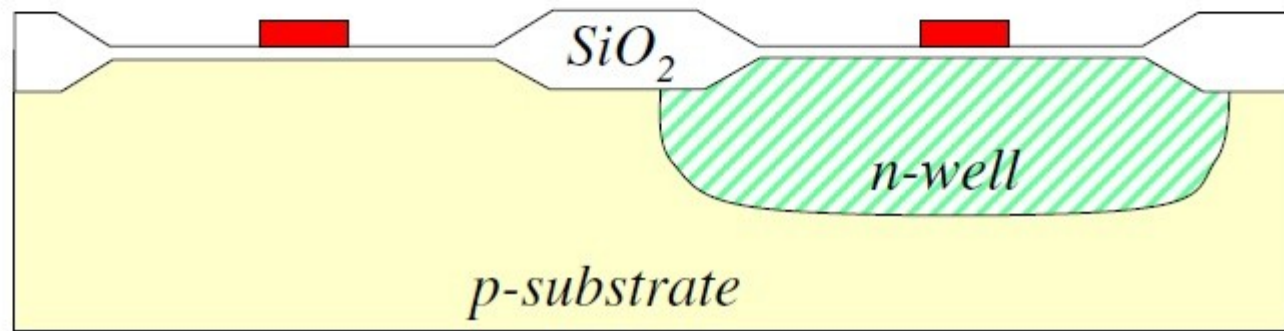


Mask 3 : Polysilicon Gate

- A high quality thin oxide is grown in the active area ($\sim 100 \text{ \AA} \rightarrow 300 \text{ \AA}$)
- *Mask 3* is used to deposit the polysilicon gate (*most critical step*)

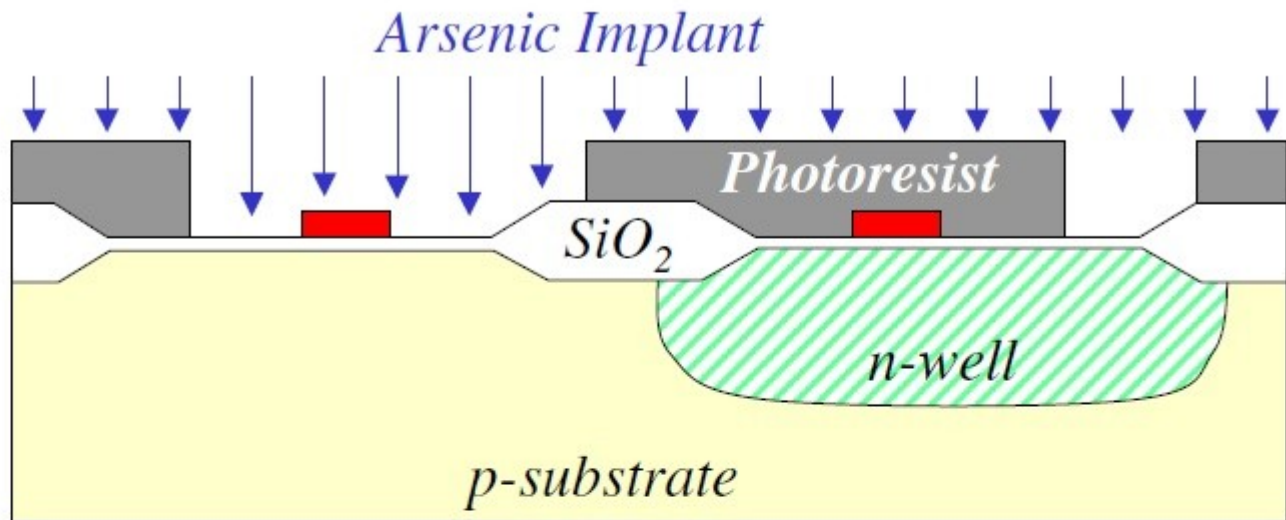


The polysilicon layer is usually arsenic doped (n-type). The photolithography in this step is the most demanding since it requires the finest resolution to create the narrow MOS channels.

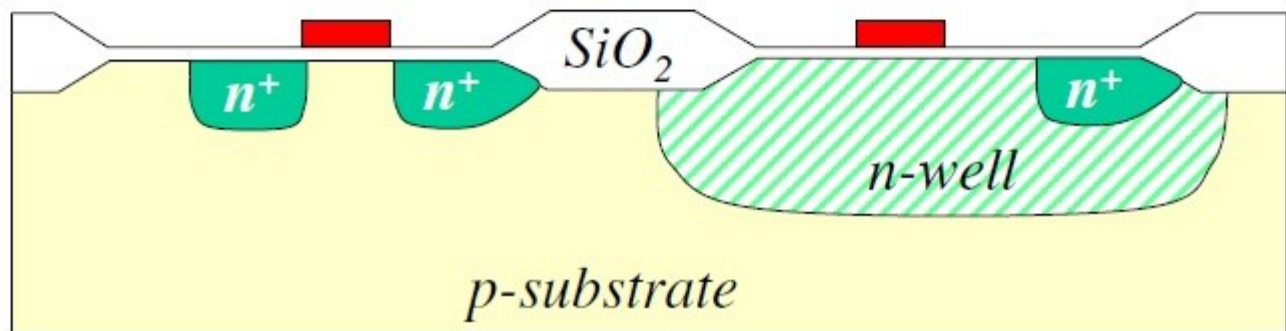
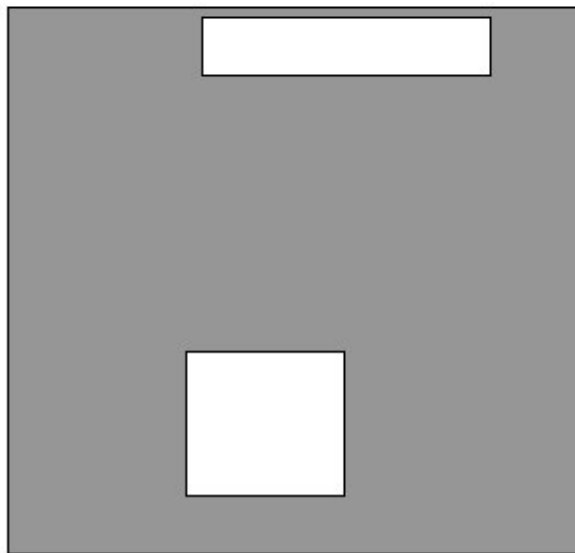


Mask 4 : n+ Diffusion

- *Mask 4* is used to control a heavy arsenic implant and create the source and drain of the n-channel devices.
- This is a **self-aligned** structure.

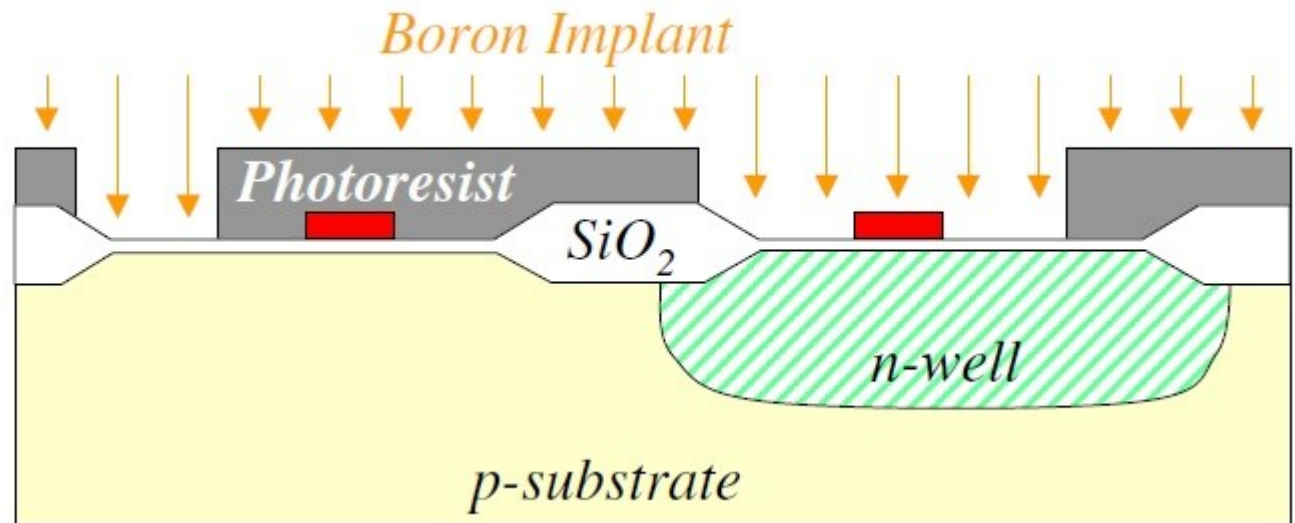


The polysilicon gate acts like a barrier for this implant to protect the channel region.

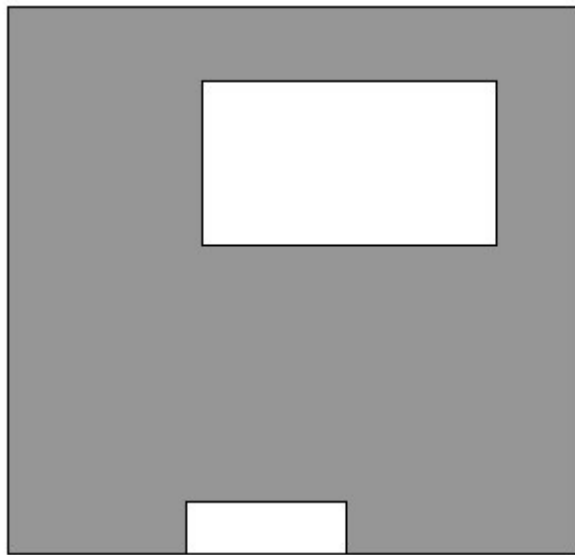
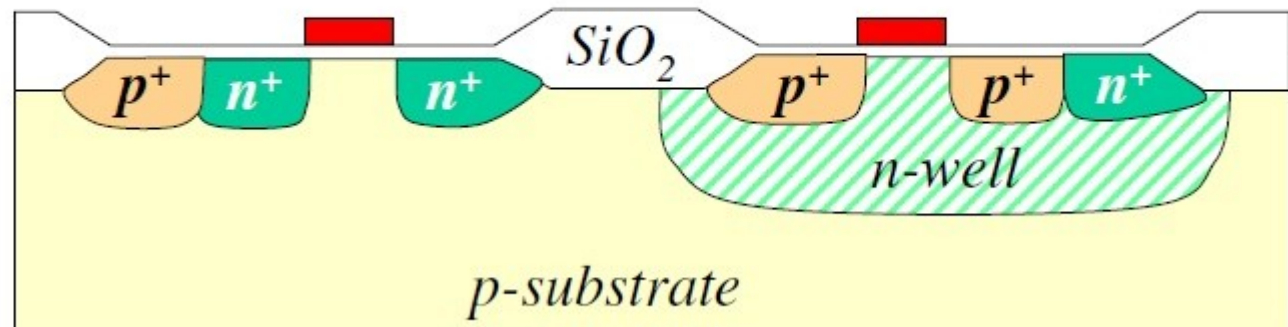


Mask 5 - p+ diffusion

- *Mask 5* is used to control a heavy Boron implant and create the source and drain of the n-channel devices.
- This is a self-aligned structure.

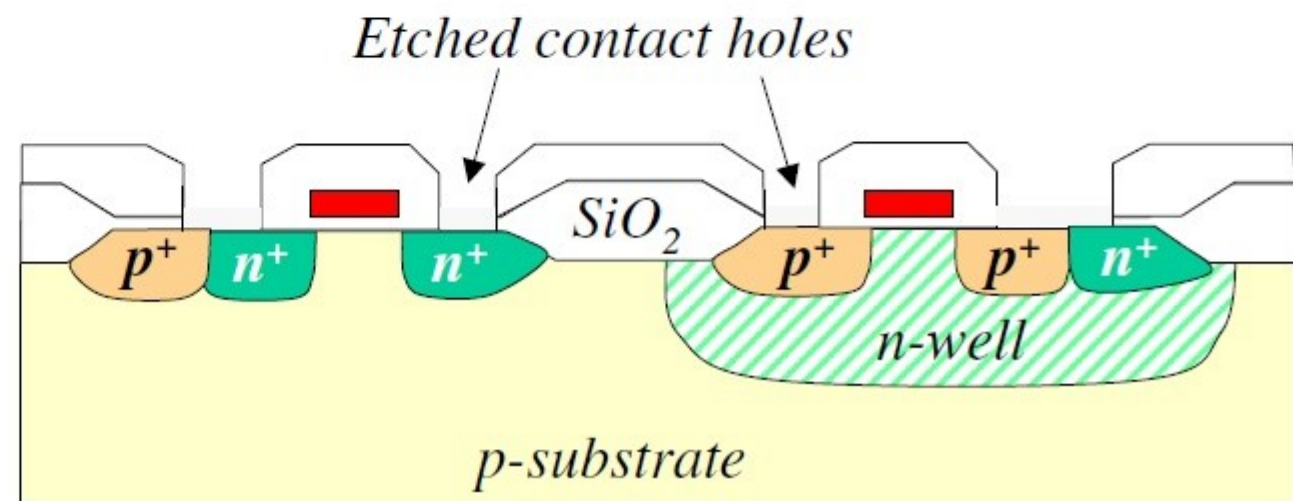
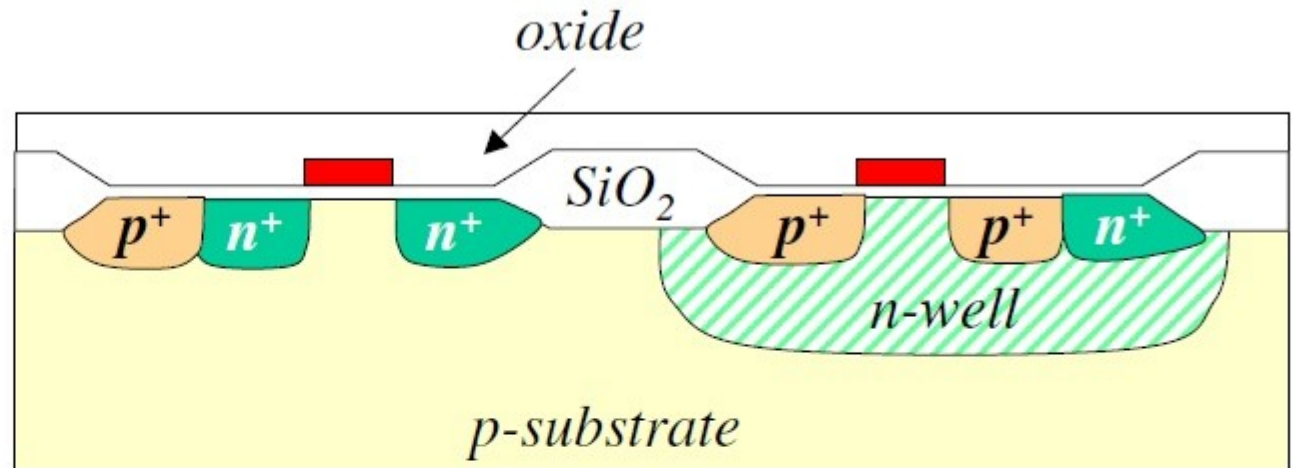
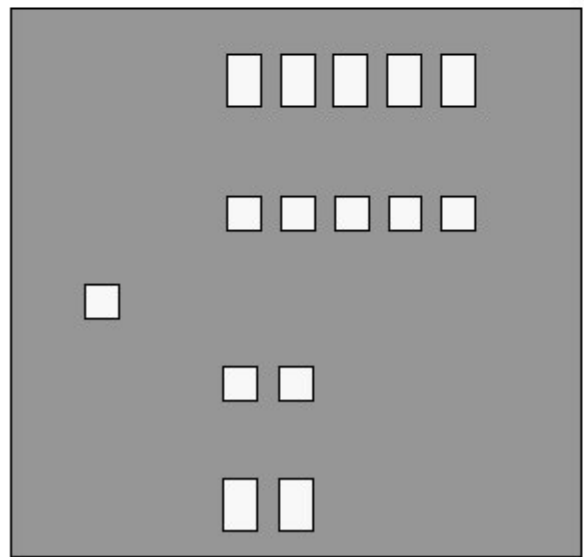


The polysilicon gate acts like a barrier for this implant to protect the channel region.



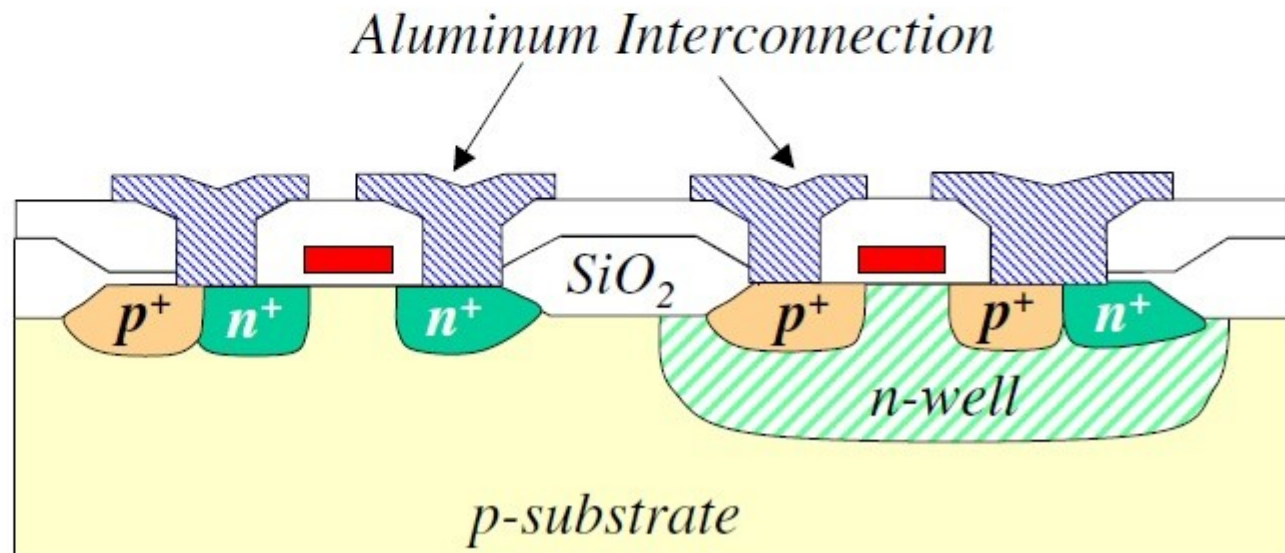
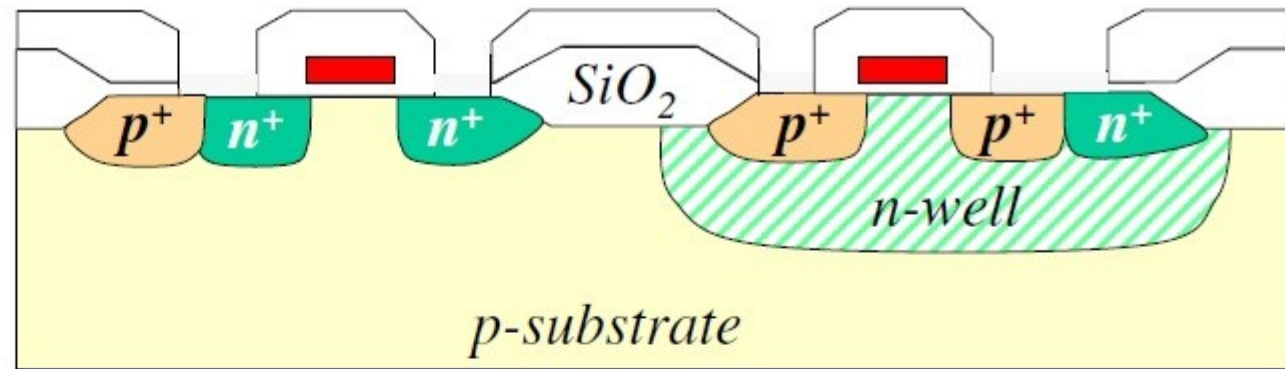
Mask 6 - Contact Holes

- A thin layer of oxide is deposited over the entire wafer
- *Mask 6* is used to pattern the contact holes
- Etching opens the holes.

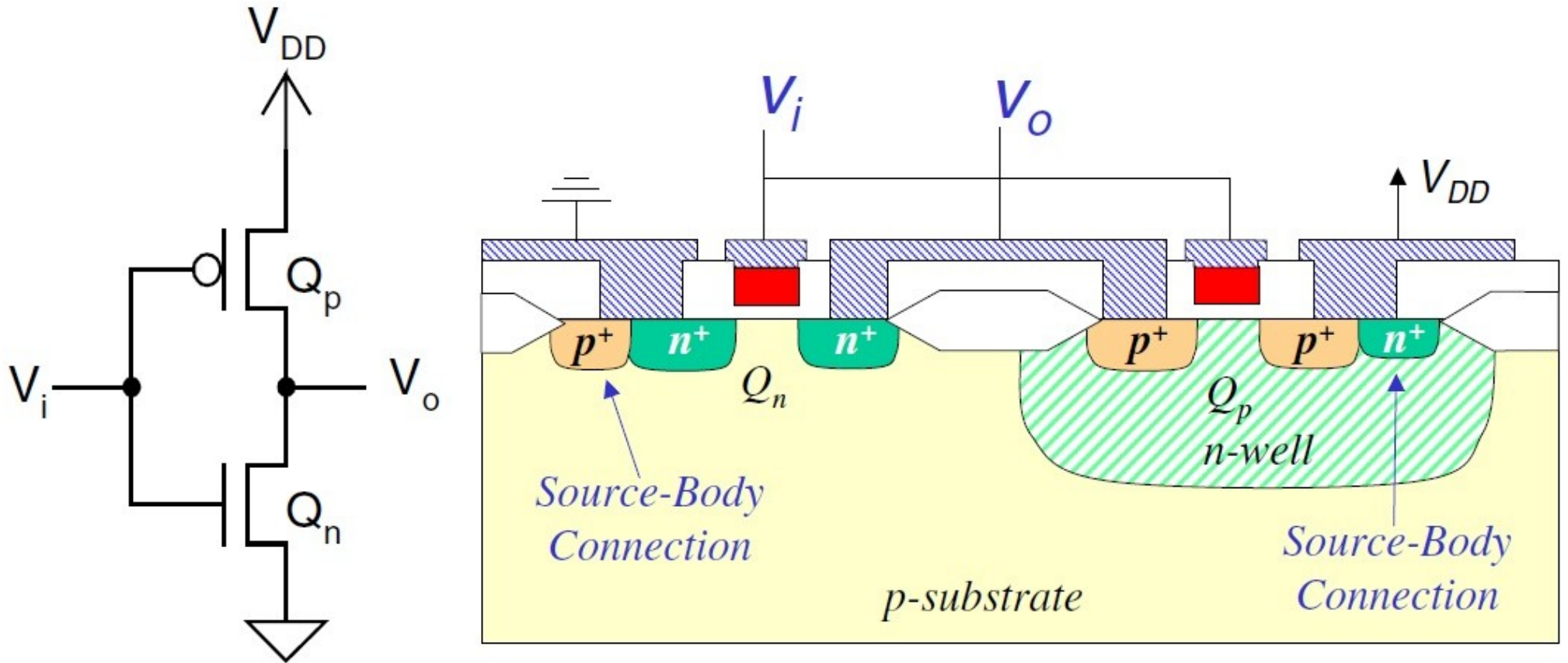


Mask 7 : Metalization

- A thin layer of aluminum is evaporated or sputtered onto the wafer.
- *Mask 7* is used to pattern the interconnection.

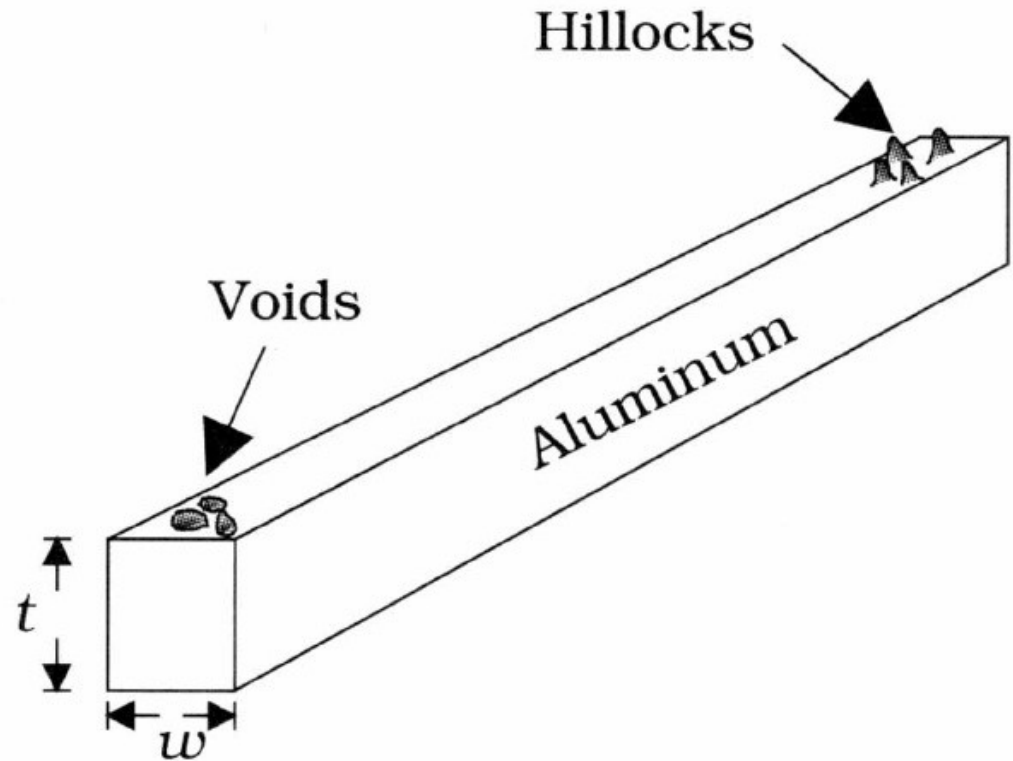


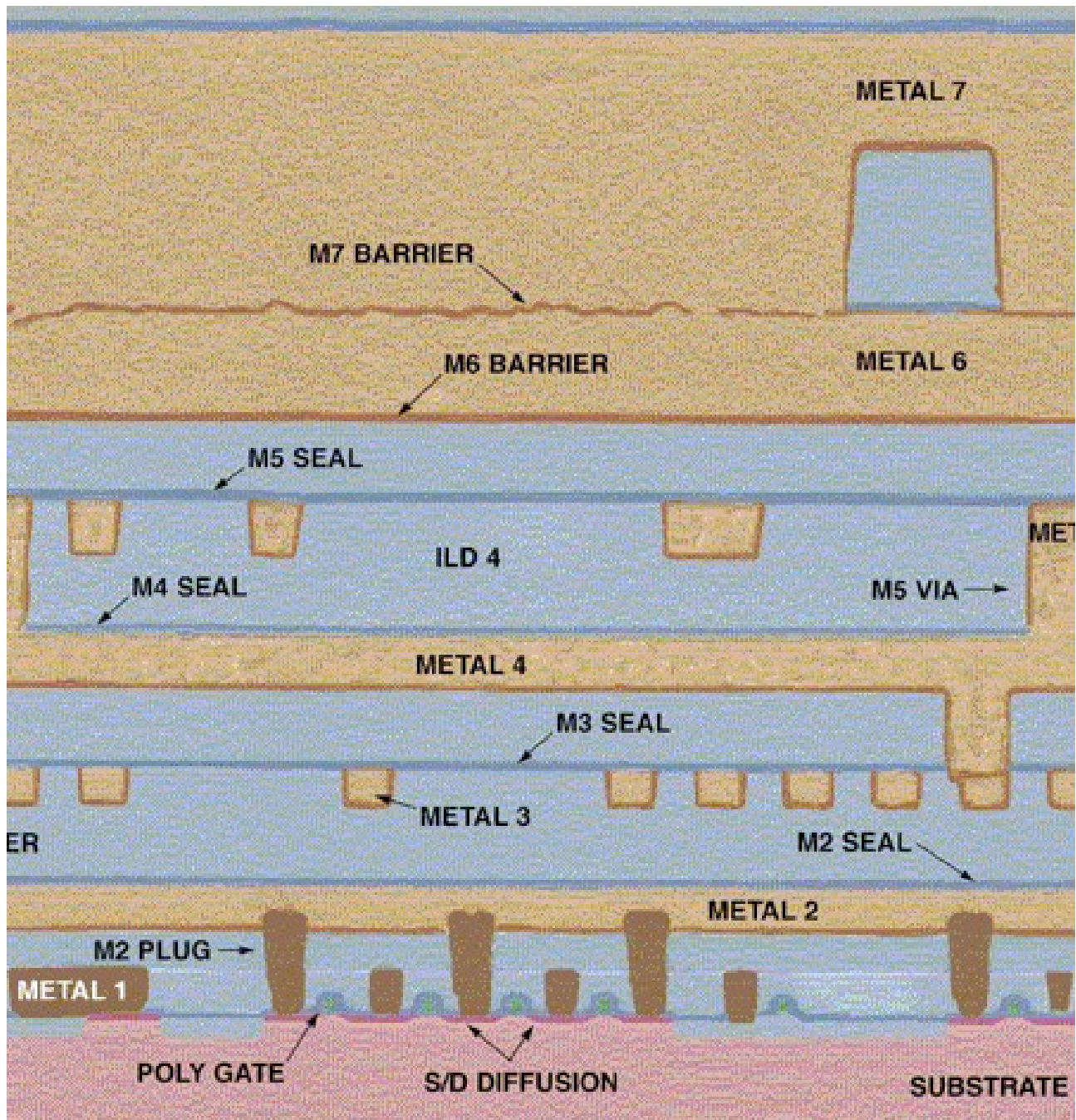
Cross section of the CMOS inverter

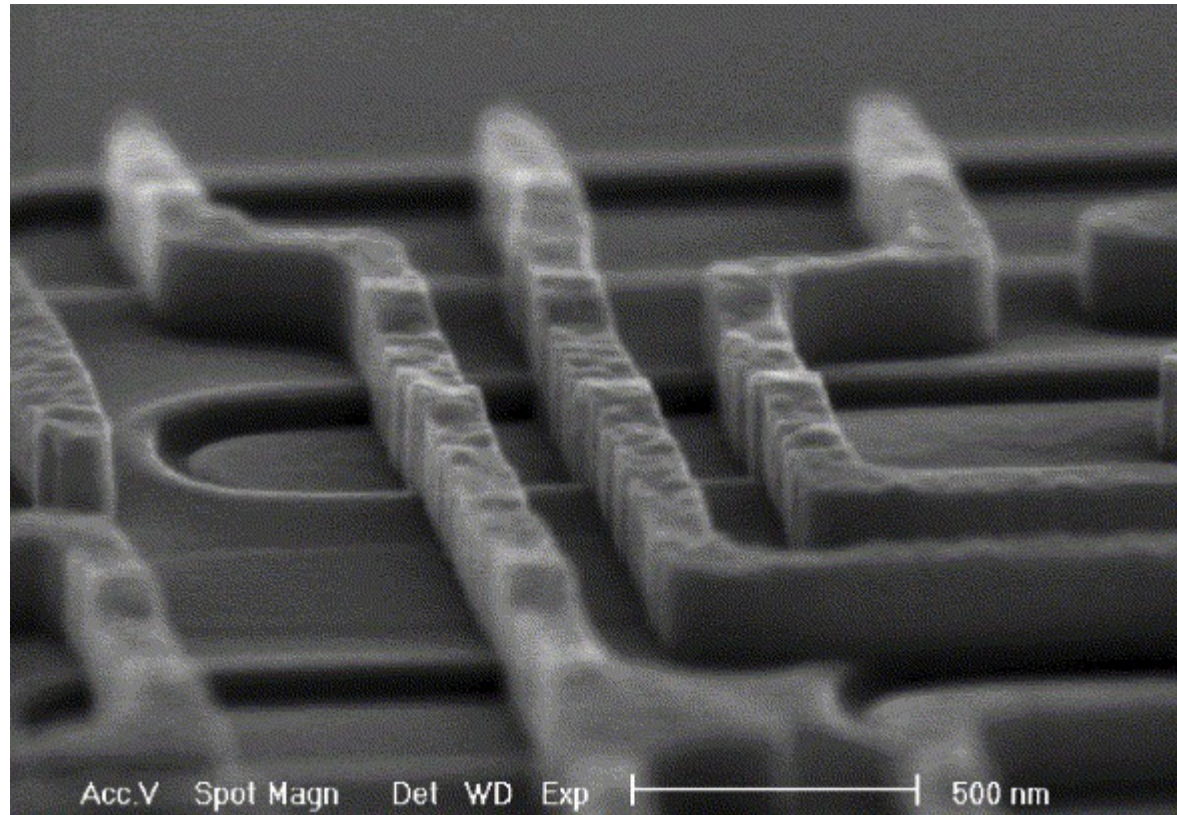


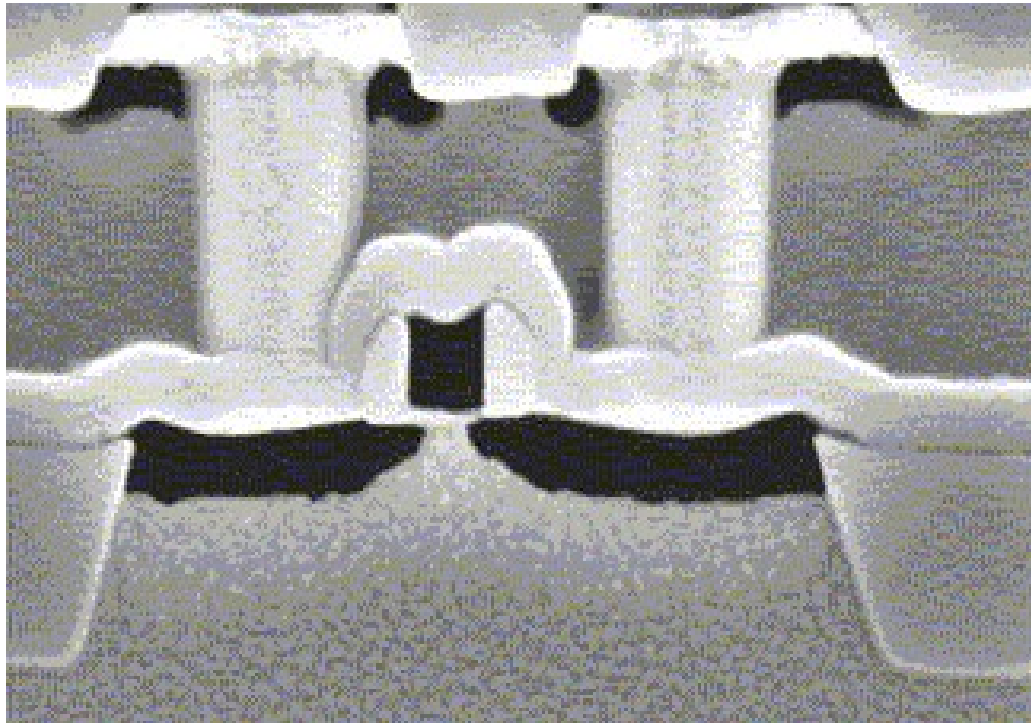
Metal

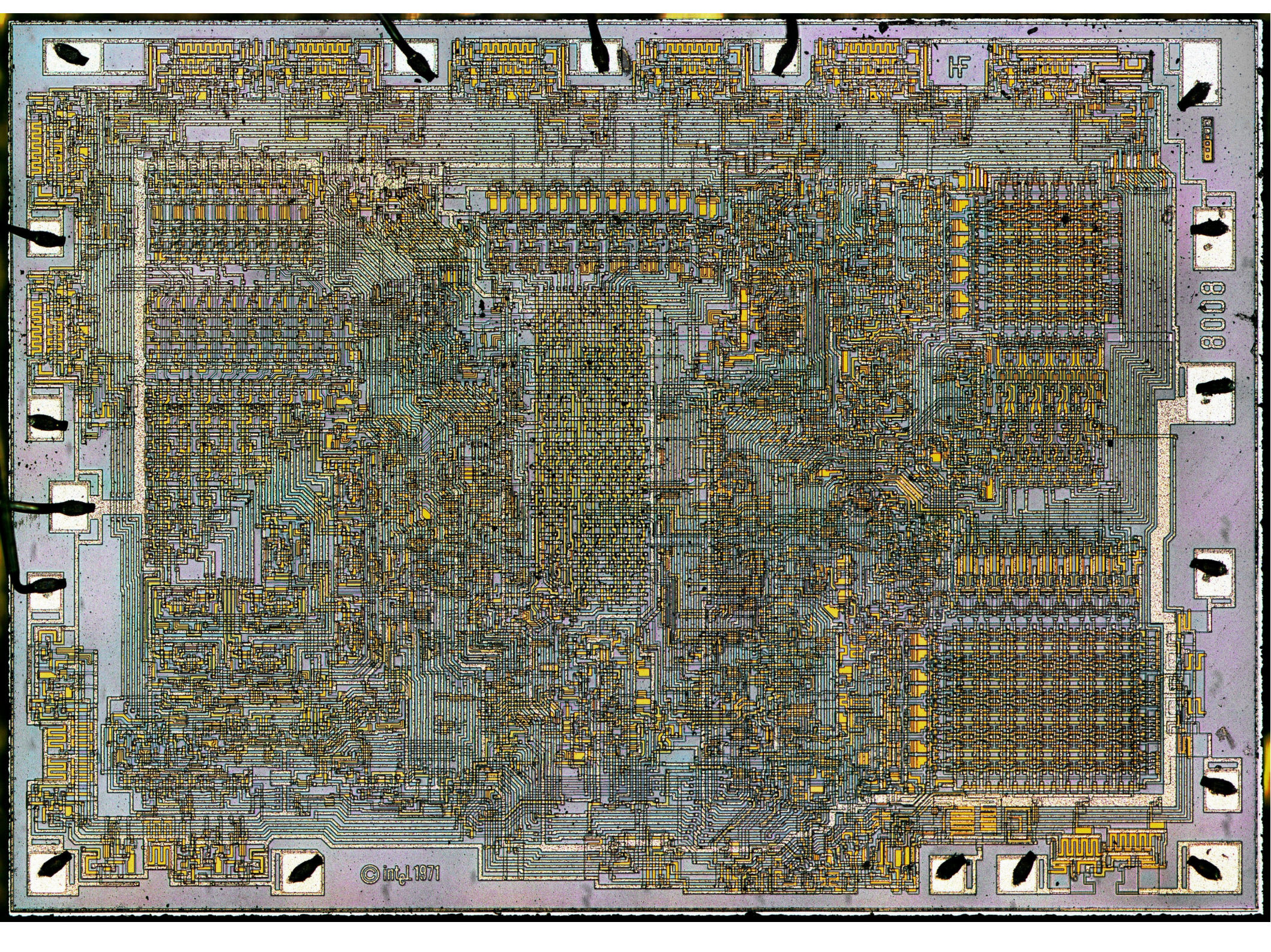
- Aluminum (Al)
 - Material or metal layers
 - Suffers electromigration
- Copper
 - Half resistance of Al
 - Much harder process











© Intel 1971

8008

Bonding pad

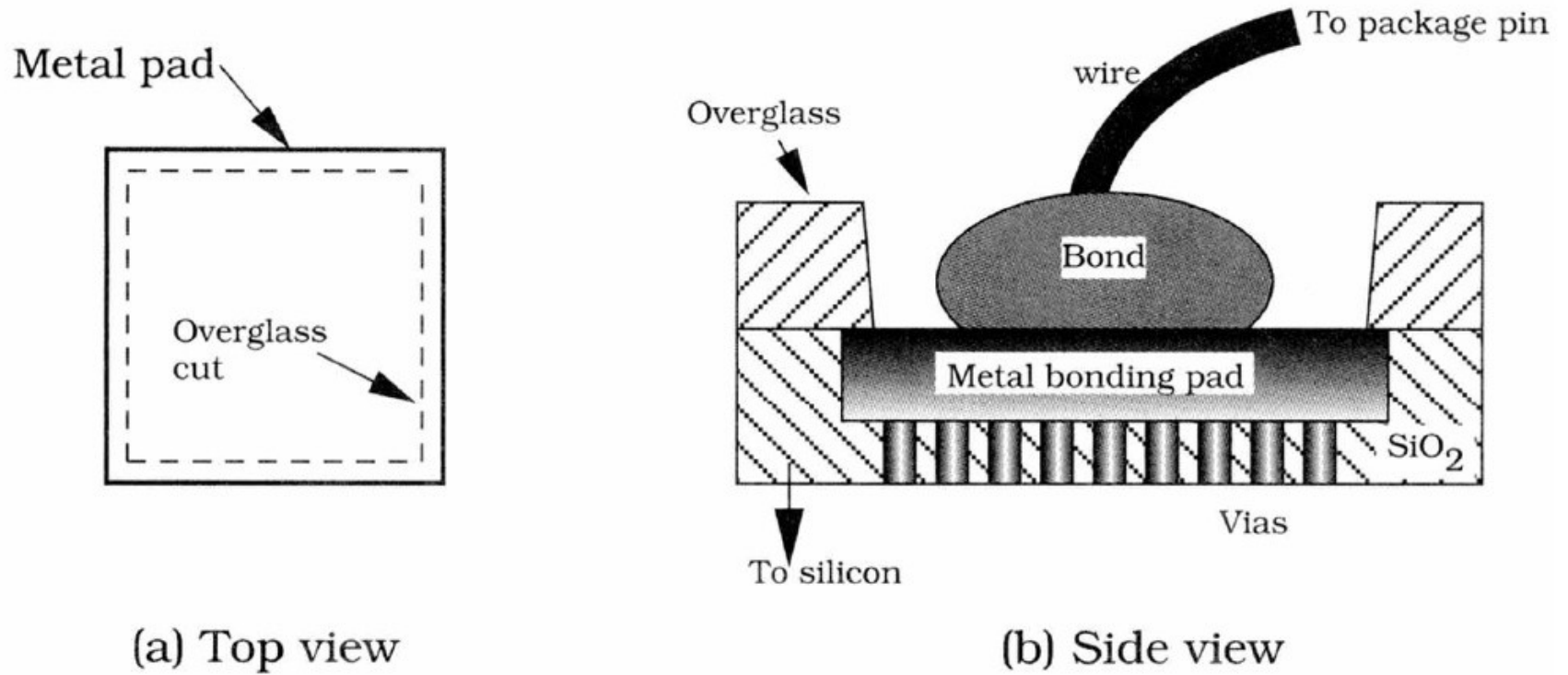


Figure 4.19 Bonding pad structure

Transistor Cross Section

